

29F52•29F53 8-Bit Registered Transceiver

General Description

The 29F52 and 29F53 are 8-bit registered transceivers. Two 8-bit back to back registers store data flowing in both directions between two bidirectional buses. Separate clock, clock enable and 3-STATE output enable signals are provided for each register. The A₀-A₇ output pins are guaranteed to sink 24 mA while the B₀-B₇ output pins are designed for 64 mA.

The 29F53 is an inverting option of the 29F52. Both transceivers are AMD Am2952/2953 functional equivalents.

Features

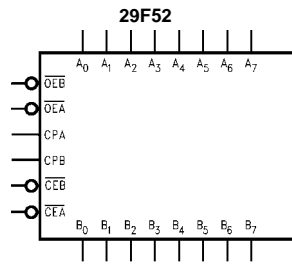
- 8-bit registered transceivers
- Separate clock, clock enable and 3-STATE output enable provided for each register
- AMD Am2952/2953 functional equivalents
- Both inverting and non-inverting options available
- 24-Pin slimline package

Ordering Code:

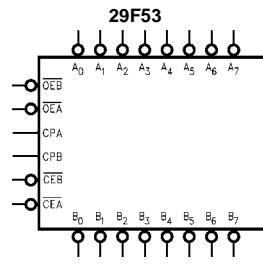
Order Number	Package Number	Package Description
29F52SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
29F52SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide
29F53SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

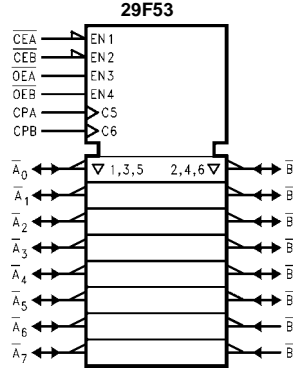
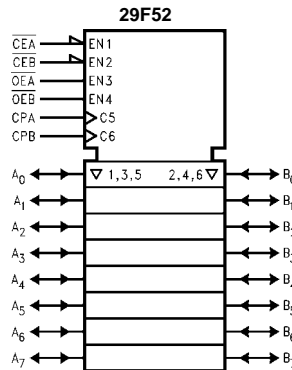
Logic Symbols



IEEE/IEC

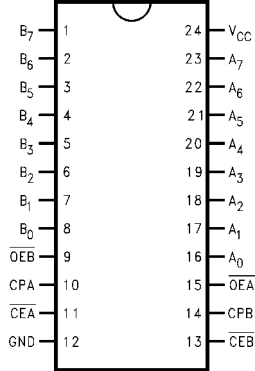


IEEE/IEC

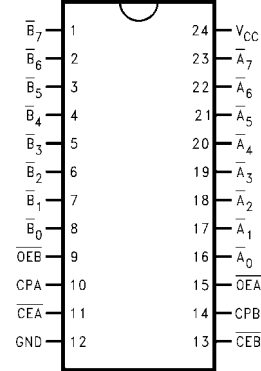


Connection Diagrams

Pin Assignment for DIP and SOIC
29F52



Pin Assignment for DIP
29F53



Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
A ₀ -A ₇	A-Register Inputs/ B-Register 3-STATE Outputs	3.5/1.083	70 μ A/0.65 mA
B ₀ -B ₇	B Register Inputs/ A-Register 3-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)
\overline{OE}	Output Enable A-Register	3.5/1.083	70 μ A/0.65 mA
CPA	A-Register Clock	600/106.6 (80)	-12 mA/64 mA (48 mA)
\overline{CEA}	A-Register Clock Enable	1.0/1.0	20 μ A/-0.6 mA
\overline{OEB}	Output Enable B-Register	1.0/1.0	20 μ A/-0.6 mA
CPB	B-Register Clock	1.0/1.0	20 μ A/-0.6 mA
\overline{CEB}	B-Register Clock Enable	1.0/1.0	20 μ A/-0.6 mA

Output Control

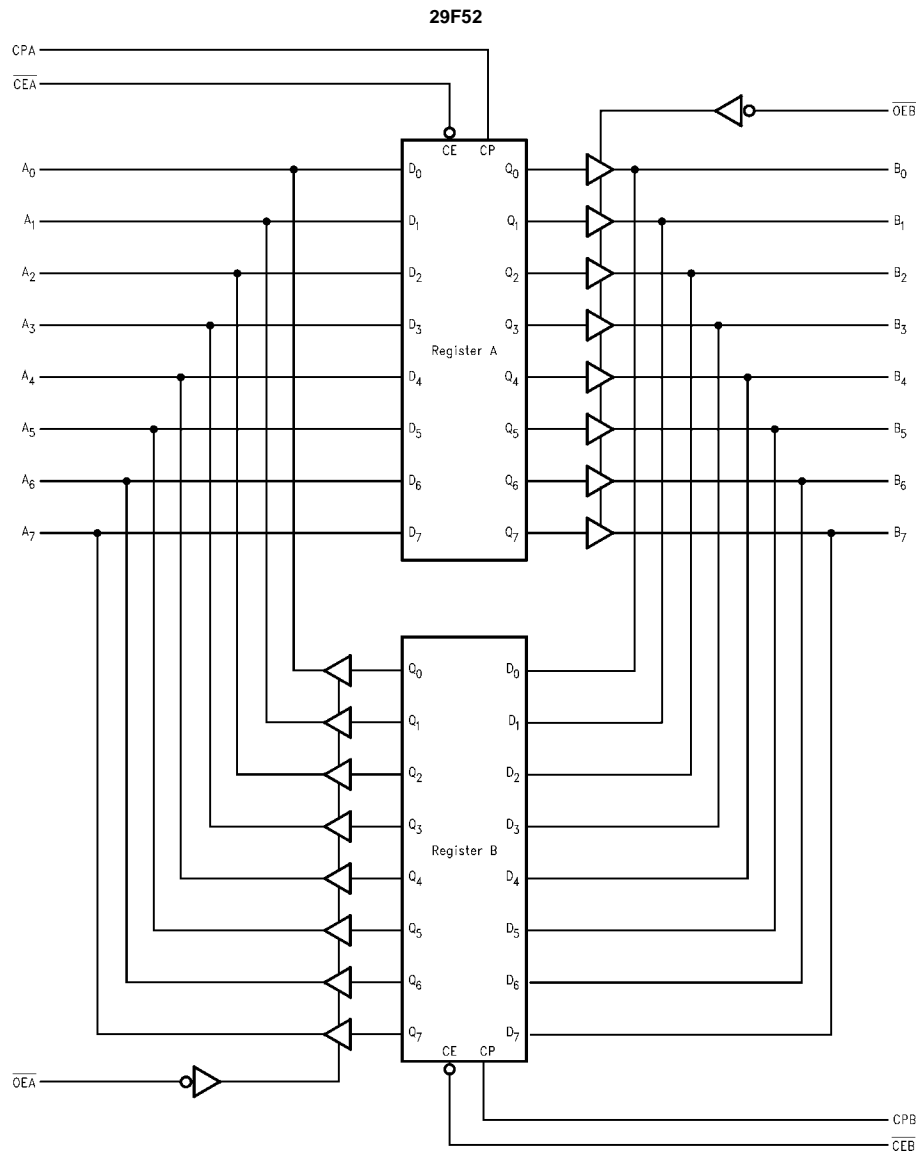
OE	Internal Q	Y-Output		Function
		29F52	29F53	
H	X	Z	Z	Disable Outputs
L	L	L	H	Enable Outputs
L	H	H	L	

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial
 Z = HIGH Impedance
 N = LOW-to-HIGH Transition
 NC = No Change

Register Function Table (Applies to A or B Register)

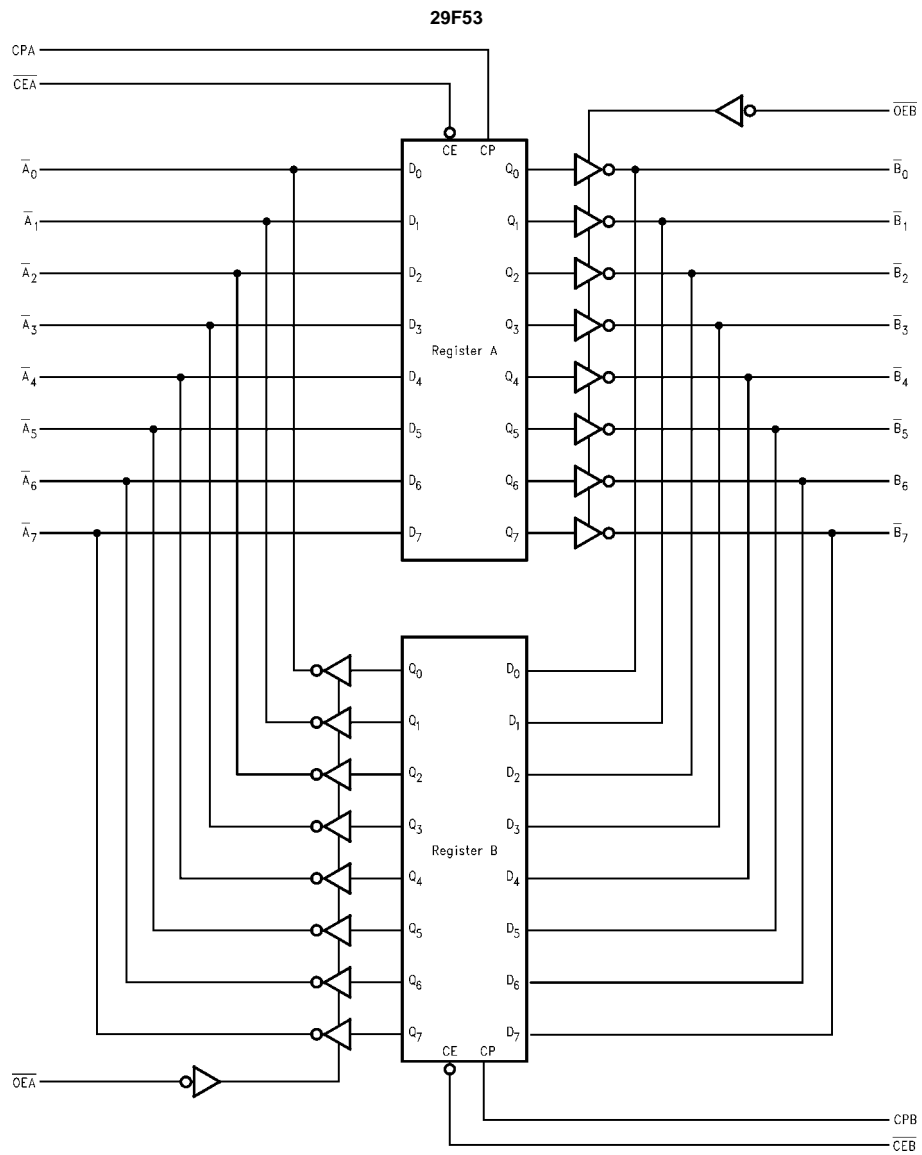
Inputs			Internal Q	Function
D	CP	CE		
X	X	H	NC	Hold Data
L	N	L	L	Load Data
H	N	L	H	

Block Diagrams



29F52•29F53

Block Diagrams (continued)



Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with V _{CC} = 0V)	
Standard Output	-0.5V to V _{CC}
3-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated I _{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA (Non I/O Pins)
V _{OH}	Output HIGH Voltage	10% V _{CC} 10% V _{CC} 10% V _{CC} 5% V _{CC} 5% V _{CC}	2.5 2.4 2.0 2.7 2.7		V	Min	I _{OH} = -1 mA (A _n) I _{OH} = -3 mA (A _n , B _n) I _{OH} = -15 mA (B _n) I _{OH} = -1 mA (A _n) I _{OH} = -3 mA (A _n , B _n)
V _{OL}	Output LOW Voltage	10% V _{CC} 10% V _{CC}		0.5 0.55	V	Min	I _{OL} = 24 mA (A _n) I _{OL} = 64 mA (B _n)
I _{IH}	Input HIGH Current			20	μA	Max	V _{IN} = 2.7V (Non-I/O Pins)
I _{BVI}	Input HIGH Current Breakdown Test			100	μA	Max	V _{IN} = 7.0V (Non-I/O Pins)
I _{BVIT}	Input HIGH Current Breakdown Test (I/O)			1.0	mA	Max	V _{IN} = 5.5V (A _n , B _n)
I _{IL}	Input LOW Current			-0.6	mA	Max	V _{IN} = 0.5V (Non-I/O Pins)
I _{IH} + I _{OZH}	Output Leakage Current			70	μA	Max	V _{OUT} = 2.7V (A _n , B _n)
I _{IL} + I _{OZL}	Output Leakage Current			-650	μA	Max	V _{OUT} = 0.5V (A _n , B _n)
I _{OS}	Output Short-Circuit Current	-60 -100		-150 -225	mA	Max	V _{OUT} = 0V (A _n) V _{OUT} = 0V (B _n)
I _{CEx}	Output HIGH Leakage Current			250	μA	Max	V _{OUT} = V _{CC} (A _n , B _n)
I _{ZZ}	Bus Drainage Test			500	μA	0.0V	V _{OUT} = 5.25V (A _n , B _n)
I _{CCH}	Power Supply Current		130	190	mA	Max	V _O = HIGH
I _{CCL}	Power Supply Current			190	mA	Max	V _O = LOW
I _{CCZ}	Power Supply Current			190	mA	Max	V _O = HIGH Z

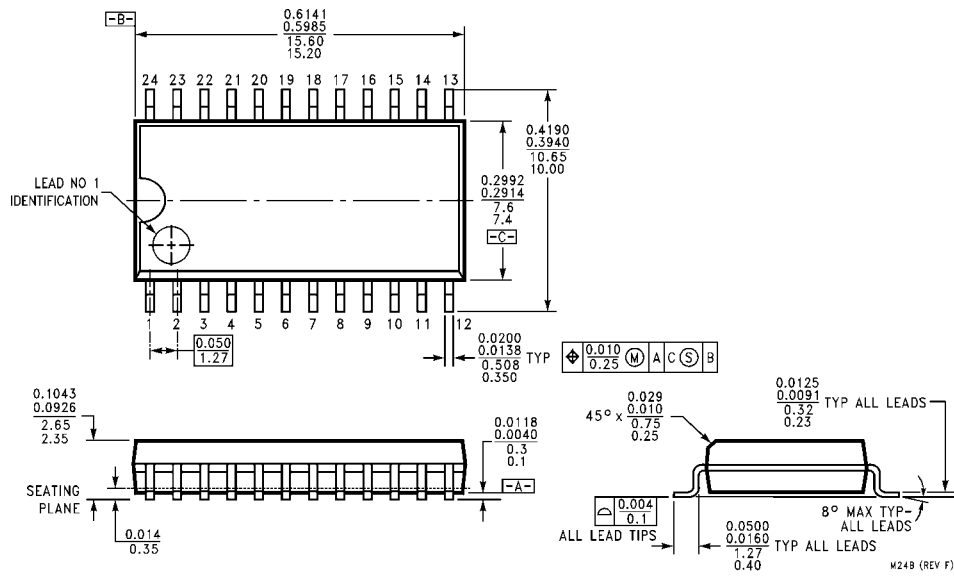
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$			$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		Units
		Min	Typ	Max	Min	Max	Min	Max	
t_{PLH}	Propagation Delay	3.0	5.5	7.5			2.5	8.5	ns
t_{PHL}	CPA or CPB to A_n or B_n	4.0	7.0	9.0			3.5	10.0	
t_{PZH}	Output Enable Time	2.5	5.5	7.5			2.0	8.5	ns
t_{PZL}	$\overline{\text{OEA}}$ or $\overline{\text{OEB}}$ to A_n or B_n	3.5	7.0	9.5			3.0	10.5	
t_{PHZ}	Output Disable Time	2.5	6.5	9.0			2.0	10.0	ns
t_{PLZ}	$\overline{\text{OEA}}$ or $\overline{\text{OEB}}$ to A_n or B_n	2.5	5.5	7.5			2.0	8.5	

AC Operating Requirements

Symbol	Parameter	$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = +5.0\text{V}$		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$		Units
		Min	Max	Min	Max	Min	Max	
$t_{S(H)}$	Setup Time, HIGH or LOW	4.0				4.5		ns
$t_{S(L)}$	A_n or B_n to CPA or CPB	4.0				4.5		
$t_{H(H)}$	Hold Time, HIGH or LOW	2.0				2.5		ns
$t_{H(L)}$	A_n or B_n to CPA or CPB	2.0				2.5		
$t_{S(H)}$	Setup Time, HIGH or LOW	1.0				1.5		ns
$t_{S(L)}$	$\overline{\text{CEA}}$ or $\overline{\text{CEB}}$ to CPA or CPB	4.0				4.5		
$t_{H(H)}$	Hold Time, HIGH or LOW	2.0				2.5		ns
$t_{H(L)}$	$\overline{\text{CEA}}$ or $\overline{\text{CEB}}$ to CPA or CPB	2.0				2.5		
$t_{W(H)}$	Pulse Width, HIGH or LOW	3.0				3.5		ns
$t_{W(L)}$	CPA or CPB	3.0				3.5		

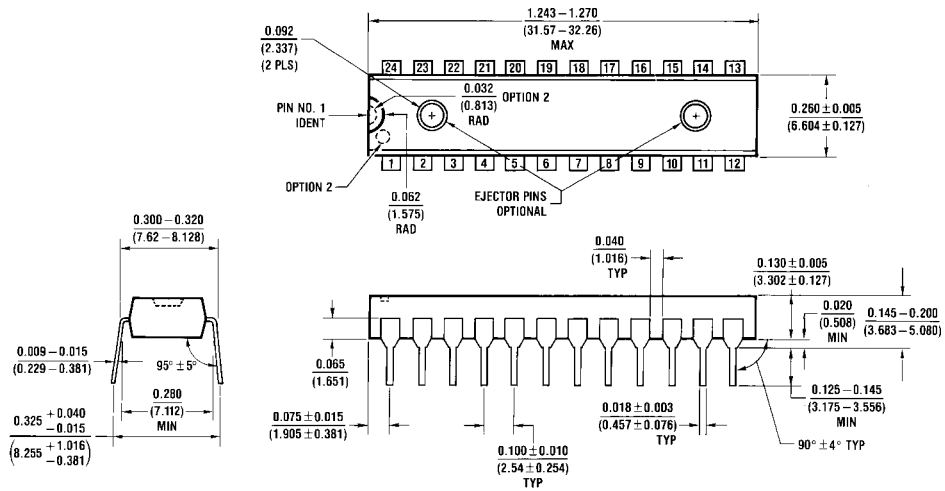
Physical Dimensions inches (millimeters) unless otherwise noted



**24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
Package Number M24B**

M24B (REV F)

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



N24C (REV F)

24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide Package Number N24C

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